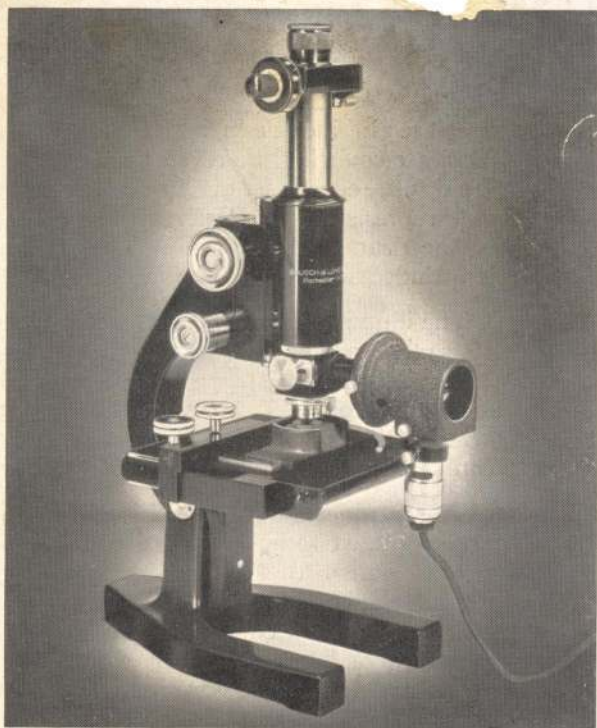


*for the rapid  
and accurate  
measurement  
of plate depth*

Plater's Microscope  
set up for use. Specimen  
holder included.



## ELECTRO-PLATERS MICROSCOPE

In response to a general demand from the electro-plating industry for a simple method to measure thickness of plating, Bausch & Lomb has developed a special electro-plater's microscope which permits rapid and accurate measurements of plating thickness. Many of these instruments are already in use and their fine performance has demonstrated their excellence for minimum thickness measurements required by the industry.

The superior optical and mechanical features that characterize all Bausch & Lomb instruments have been incorporated into the design and construction of this microscope, making it a truly precision instrument of highest quality. The instru-

ment is inexpensive, simple in construction and easy to operate. It consists of a monocular microscope stand (H type) equipped with both coarse and fine adjustments, an achromatic objective, a Filar micrometer eyepiece, a vertical illuminating unit for properly illuminating the specimen, and a mechanical stage to facilitate locating the specimen correctly in the field of the optical system. The microscope is supplied in a hardwood case with handle, lock and key.

The Filar micrometer eyepiece includes a movable hair actuated by a micrometer screw with a drum graduated in 100 divisions. Each division on the drum represents 0.000,01" on the specimen. The

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eyepiece also includes a fixed scale to facilitate counting the revolutions of the drum—each least division of the scale representing one half revolution of the drum. A calibration record is included with each instrument.

The illuminating unit consists of a 15 candle power low voltage bulb and includes a resistance for use on either A.C. or D.C., 110 volts. For other voltages suitable resistances can be supplied.

The routine to be followed in preparing plated samples for examination is similar to that used in the metallographic laboratory. A cross section of the plated sample may be placed in a brass ring and Muntz metal or solder poured around it, or to save time it may be held in a regular laboratory hose clamp to facilitate handling during prepara-

tion. The sample is then rough ground to produce a flat surface, followed with 0000 emery paper, and finally polished with levigated alumina on broadcloth.

To facilitate handling the prepared specimen on the microscope stage, a specimen holder is recommended. The use of molding clay aids in mounting the specimen in the holder which fits readily into the mechanical stage. This holder is included as a part of the complete microscope.

For those who already may be equipped with a microscope and wish to make plating measurements, the necessary objective, micrometer eyepiece, and vertical illuminating unit are offered. In such cases, the micrometer eyepiece cannot be calibrated, but a stage micrometer for doing this can be obtained.

## SPECIFICATIONS AND PRICES

Description	Catalog No.	Code Word	Price
Electro-Plater's Microscope, as described, in case. . . . .	31-21-45-61	<i>Aitgl</i>	\$170.00
Vertical Illuminating Unit for 110-volt A. C. or D. C..	31-33-45-63	<i>Afvol</i>	47.00
Achromatic Objective, 4 mm short mounted. . . . .	31-13-31-01	<i>Afsaf</i>	18.75
Filar Micrometer Eyepiece, uncalibrated. . . . .	31-16-50	<i>Acovj</i>	45.00
Stage Micrometer, metal, ruled to .1 and .01 mm*. . . . .	31-16-97	<i>Acoym</i>	12.00
Specimen Holder, (included in 31-21-45-61). . . . .	31-59-12	<i>Afodz</i>	1.75

For a complete description and listing of Bausch & Lomb metallurgical microscopes and complete metallographic equipment, send for catalog E-225.

*The prices herein are subject to change without notice and to increase for taxes, excises or other charges imposed by governmental authorities with respect to articles listed herein or to the sale thereof.*

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